Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | ISHIDA ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,922,452	07-2005	Sandberg, David	375/346
*	В	US-6,882,680	04-2005	Oleynik, Vladislav A.	375/147
*	С	US-5,402,443	03-1995	Wong, Hee	375/226
*	D	US-6,263,034	07-2001	Kanack et al.	375/371
*	E	US-6,442,214	08-2002	Boleskei et al.	375/299
*	F	US-5,757,652	05-1998	Blazo et al.	702/69
*	G	US-6,661,860	12-2003	Gutnik et al.	375/354
*	н	US-6,661,836	12-2003	Dalal et al.	375/226
*	ı	US-4,654,861	03-1987	Godard, Dominique	375/226
	J	US-			
	К	US-			
1	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν				,	
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
į	υ	Voorakaranam et al "Low-cost Jitter Measurement Technique for Phase-Locked Loop", Proceedings of the 43rd IEEE Midwest Symposium on Circuits and Systems, Volume 2, 8-11 Aug. 2000 Page(s) 956 - 959.				
	٧					
	8					
	x					

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.